



Preliminary data

BSV 236SP

OptiMOS®-P Small-Signal-Transistor

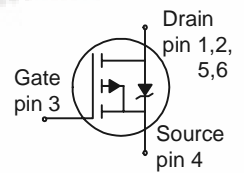
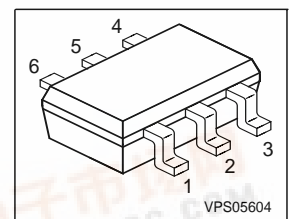
Feature

- P-Channel
- Enhancement mode
- Super Logic Level (2.5 V rated)
- 150°C operating temperature
- Avalanche rated
- dv/dt rated

Product Summary

| | | |
|--------------|------|----|
| V_{DS} | -20 | V |
| $R_{DS(on)}$ | 175 | mΩ |
| I_D | -1.5 | A |

SOT-363



| Type | Package | Ordering Code | Marking |
|-----------|---------|---------------|---------|
| BSV 236SP | SOT-363 | Q67042-S4070 | X2s |

Maximum Ratings, at $T_j = 25\text{ }^\circ\text{C}$, unless otherwise specified

| Parameter | Symbol | Value | Unit |
|---|--------------------|-------------|-------------------|
| Continuous drain current | I_D | -1.5 | A |
| $T_A=25\text{ }^\circ\text{C}$ | | -1.5 | |
| $T_A=70\text{ }^\circ\text{C}$ | | -1.2 | |
| Pulsed drain current | $I_D \text{ puls}$ | -6 | |
| $T_A=25\text{ }^\circ\text{C}$ | | | |
| Avalanche energy, single pulse | E_{AS} | 9.5 | mJ |
| $I_D=-1.5\text{ A}$, $V_{DD}=-10\text{ V}$, $R_{GS}=25\text{ }\Omega$ | | | |
| Reverse diode dv/dt | dv/dt | -6 | kV/ μs |
| $I_S=-1.5\text{ A}$, $V_{DS}=-16\text{ V}$, $di/dt=200\text{ A}/\mu\text{s}$, $T_{jmax}=150\text{ }^\circ\text{C}$ | | | |
| Gate source voltage | V_{GS} | ± 12 | V |
| Power dissipation | P_{tot} | 0.56 | W |
| $T_A=25\text{ }^\circ\text{C}$ | | | |
| Operating and storage temperature | T_j, T_{stg} | -55... +150 | $^\circ\text{C}$ |
| IEC climatic category; DIN IEC 68-1 | | 55/150/56 | |



Thermal Characteristics

| Parameter | Symbol | Values | | | Unit |
|--|------------|--------|------|------|------|
| | | min. | typ. | max. | |
| Characteristics | | | | | |
| Thermal resistance, junction - soldering point | R_{thJS} | - | - | 90 | K/W |
| SMD version, device on PCB: | R_{thJA} | - | - | 220 | |
| @ min. footprint @ 6 cm ² cooling area ¹⁾ | | - | - | 110 | |

Electrical Characteristics, at $T_j = 25\text{ }^\circ\text{C}$, unless otherwise specified

| Parameter | Symbol | Values | | | Unit |
|--|---------------|--------|-------------|------------|---------------|
| | | min. | typ. | max. | |
| Static Characteristics | | | | | |
| Drain-source breakdown voltage $V_{GS}=0, I_D=-250\mu\text{A}$ | $V_{(BR)DSS}$ | -20 | - | - | V |
| Gate threshold voltage, $V_{GS} = V_{DS}$ $I_D=-8\mu\text{A}$ | $V_{GS(th)}$ | -0.6 | -0.9 | -1.2 | |
| Zero gate voltage drain current $V_{DS}=-20\text{V}, V_{GS}=0, T_j=25^\circ\text{C}$ $V_{DS}=-20\text{V}, V_{GS}=0, T_j=150^\circ\text{C}$ | I_{DSS} | - | -0.1 -10 | -1 -100 | μA |
| Gate-source leakage current $V_{GS}=-12\text{V}, V_{DS}=0$ | I_{GSS} | - | -10 | -100 | |
| Drain-source on-state resistance $V_{GS}=-2.5\text{V}, I_D=-0.8\text{A}$ | $R_{DS(on)}$ | - | 193 | 285 | m Ω |
| Drain-source on-state resistance $V_{GS}=-4.5, I_D=-1.5\text{A}$ | $R_{DS(on)}$ | - | 131 | 175 | |

¹Device on 40mm*40mm*1.5mm epoxy PCB FR4 with 6cm² (one layer, 70 μm thick) copper area for drain connection. PCB is vertical without blown air; $t \leq 10$ sec.

Electrical Characteristics, at $T_j = 25\text{ }^\circ\text{C}$, unless otherwise specified

| Parameter | Symbol | Conditions | Values | | | Unit |
|--------------------------------|--------------|--|--------|------|------|------|
| | | | min. | typ. | max. | |
| Dynamic Characteristics | | | | | | |
| Transconductance | g_{fs} | $ V_{DS} \geq 2 * I_D * R_{DS(on)max}$ $I_D = -1.2A$ | 2.2 | 4.4 | - | S |
| Input capacitance | C_{iss} | $V_{GS} = 0, V_{DS} = -15V,$ $f = 1MHz$ | - | 228 | - | pF |
| Output capacitance | C_{oss} | | - | 92 | - | |
| Reverse transfer capacitance | C_{rss} | | - | 75 | - | |
| Turn-on delay time | $t_{d(on)}$ | $V_{DD} = -10V, V_{GS} = -4.5V,$ $I_D = -1A, R_G = 6\Omega$ | - | 5.7 | 8.5 | ns |
| Rise time | t_r | | - | 8.5 | 12.7 | |
| Turn-off delay time | $t_{d(off)}$ | | - | 14.1 | 21.1 | |
| Fall time | t_f | | - | 12.2 | 18.3 | |

Gate Charge Characteristics

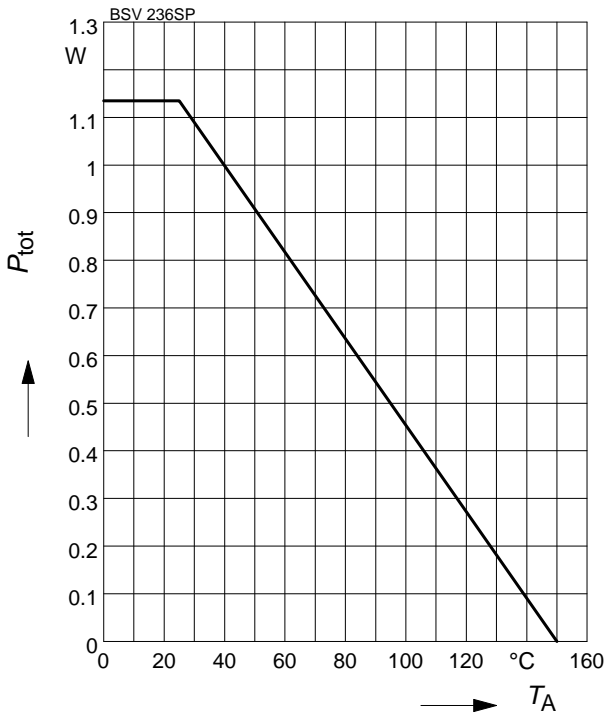
| | | | | | | |
|-----------------------|-----------------|---|---|------|------|----|
| Gate to source charge | Q_{gs} | $V_{DD} = -10V, I_D = -1.5A$ | - | -0.4 | -0.6 | nC |
| Gate to drain charge | Q_{gd} | | - | -1.8 | -2.7 | |
| Gate charge total | Q_g | $V_{DD} = -10V, I_D = -1.5A,$ $V_{GS} = 0 \text{ to } -4.5V$ | - | -3.8 | -5.7 | |
| Gate plateau voltage | $V_{(plateau)}$ | $V_{DD} = -10V, I_D = -1.5A$ | - | -1.6 | - | V |

Reverse Diode

| | | | | | | |
|--|----------|--|---|------|-------|----|
| Inverse diode continuous forward current | I_S | $T_A = 25^\circ\text{C}$ | - | - | -0.11 | A |
| Inverse diode direct current, pulsed | I_{SM} | | - | - | -6 | |
| Inverse diode forward voltage | V_{SD} | $V_{GS} = 0, I_F = I_D $ | - | 0.88 | 1.3 | V |
| Reverse recovery time | t_{rr} | $V_R = -10V, I_F = I_D ,$ $di_F/dt = 100A/\mu s$ | - | 16.4 | 20.5 | ns |
| Reverse recovery charge | Q_{rr} | | - | 3.4 | 4.3 | |

1 Power dissipation

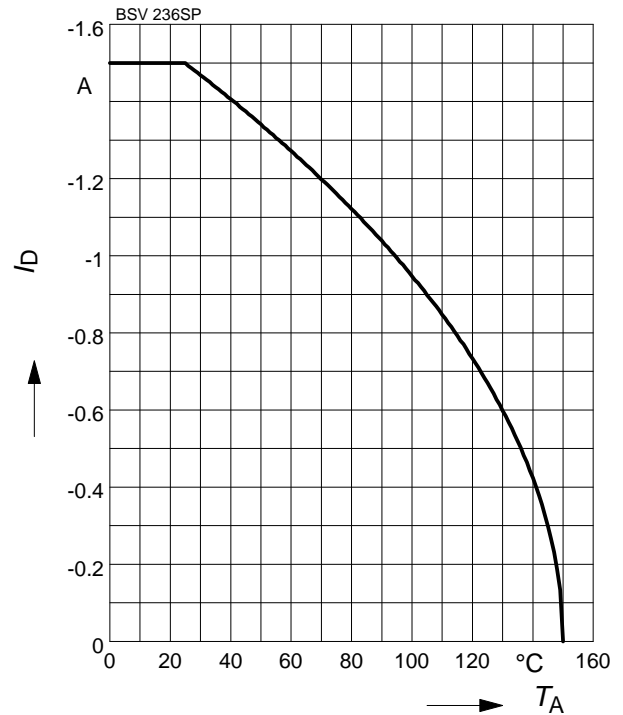
$$P_{tot} = f(T_A)$$



2 Drain current

$$I_D = f(T_A)$$

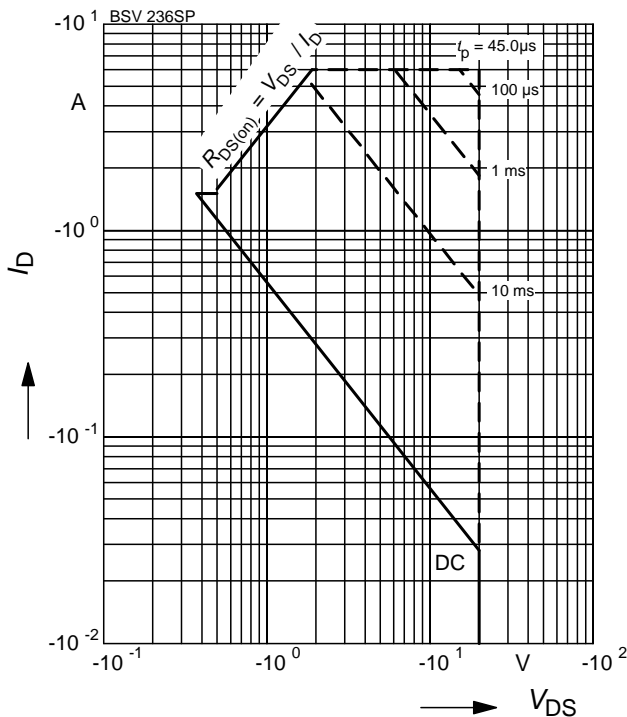
parameter: $|V_{GS}| \geq 4.5 \text{ V}$



3 Safe operating area

$$I_D = f(V_{DS})$$

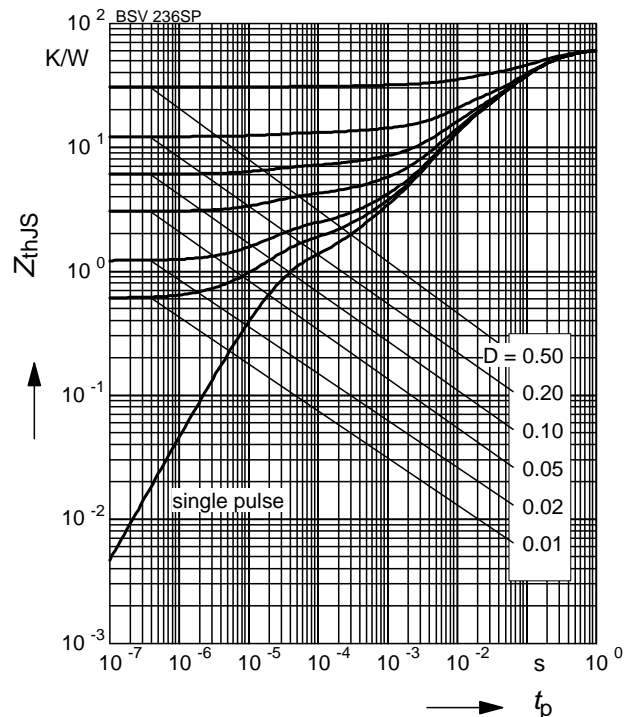
parameter: $D = 0, T_A = 25 \text{ °C}$



4 Transient thermal impedance

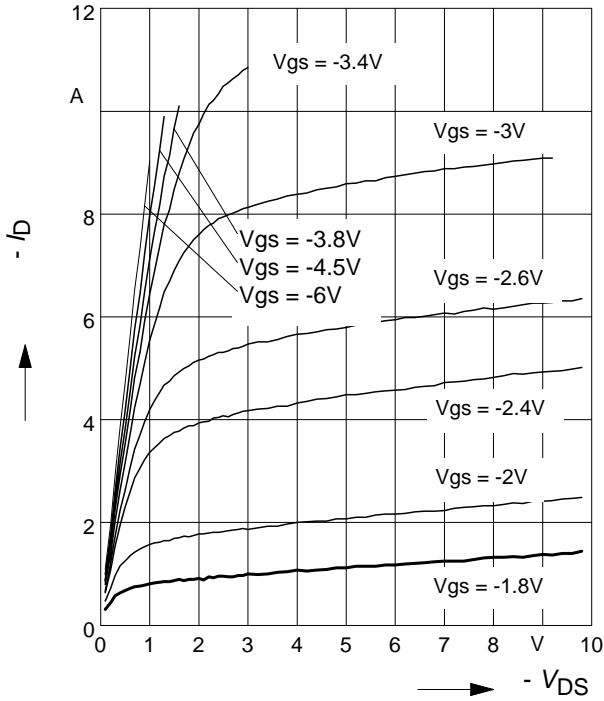
$$Z_{thJS} = f(t_p)$$

parameter: $D = t_p/T$



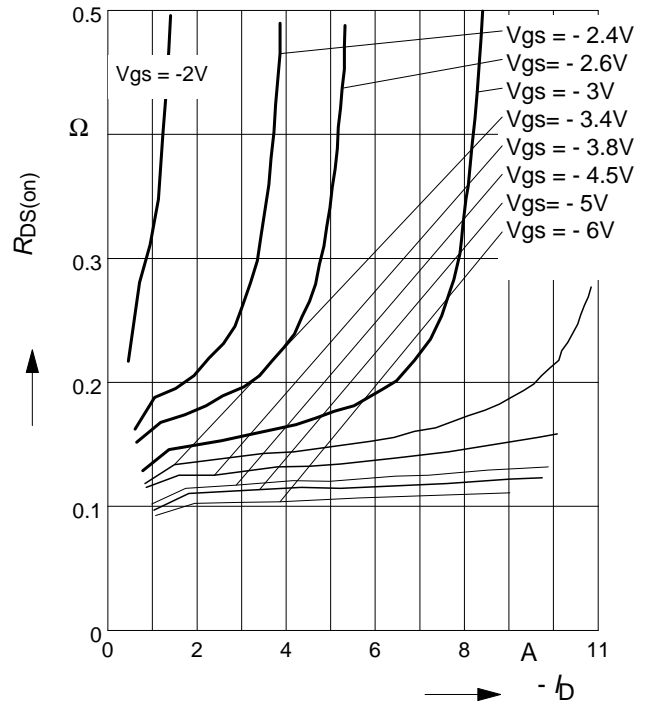
5 Typ. output characteristic

$I_D = f(V_{DS}); T_j = 25^\circ\text{C}$
parameter: $t_p = 80 \mu\text{s}$



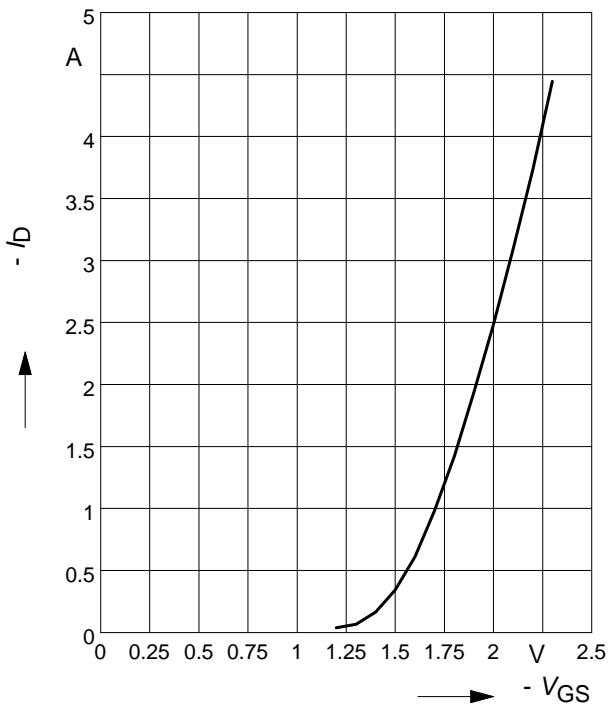
6 Typ. drain-source on resistance

$R_{DS(on)} = f(I_D)$
parameter: V_{GS}



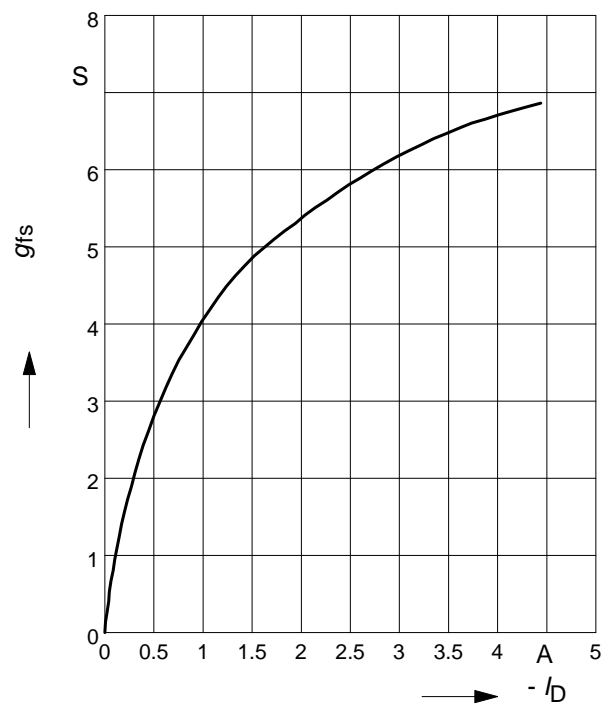
7 Typ. transfer characteristics

$I_D = f(V_{GS}); |V_{DS}| \geq 2 \times |I_D| \times R_{DS(on)max}$
parameter: $t_p = 80 \mu\text{s}$



8 Typ. forward transconductance

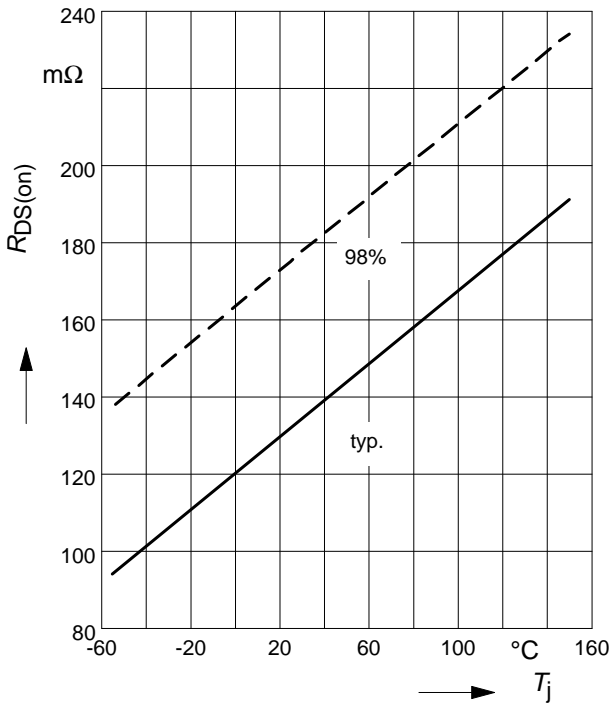
$g_{fs} = f(I_D); T_j = 25^\circ\text{C}$
parameter: $t_p = 80 \mu\text{s}$



9 Drain-source on-resistance

$$R_{DS(on)} = f(T_j)$$

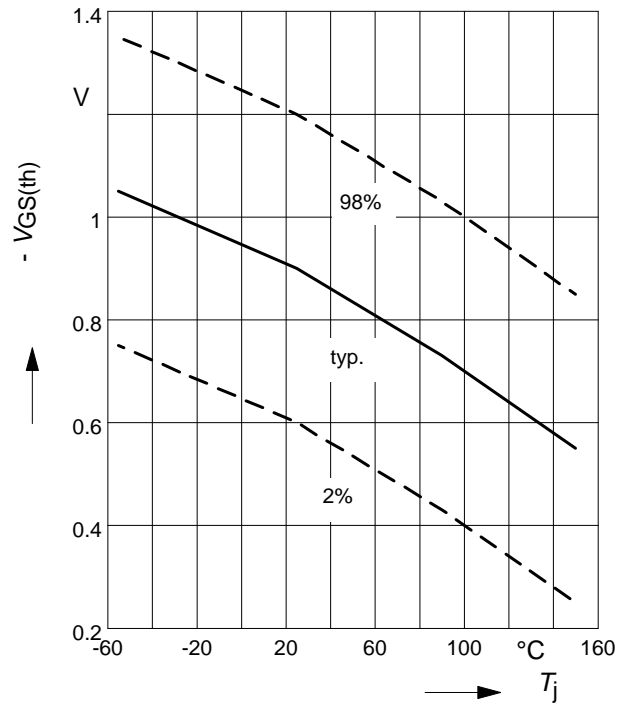
parameter: $I_D = -1.5 \text{ A}$, $V_{GS} = -4.5 \text{ V}$



10 Gate threshold voltage

$$V_{GS(th)} = f(T_j)$$

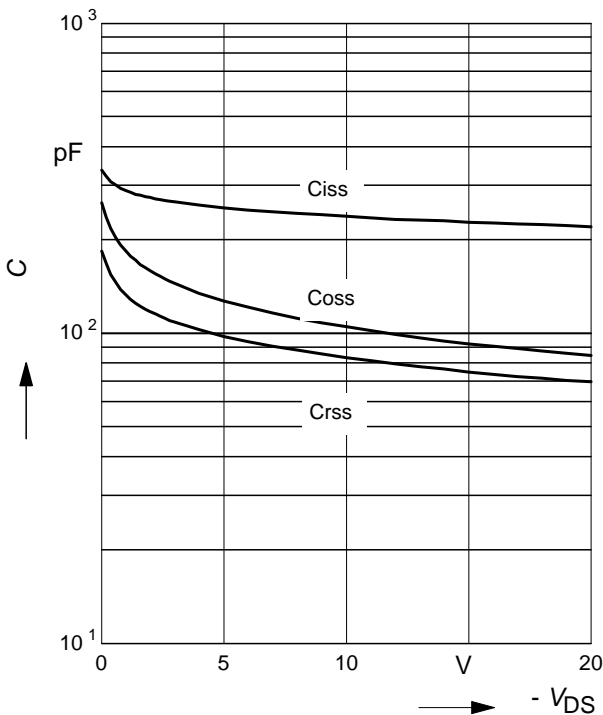
parameter: $V_{GS} = V_{DS}$, $I_D = -8 \mu\text{A}$



11 Typ. capacitances

$$C = f(V_{DS})$$

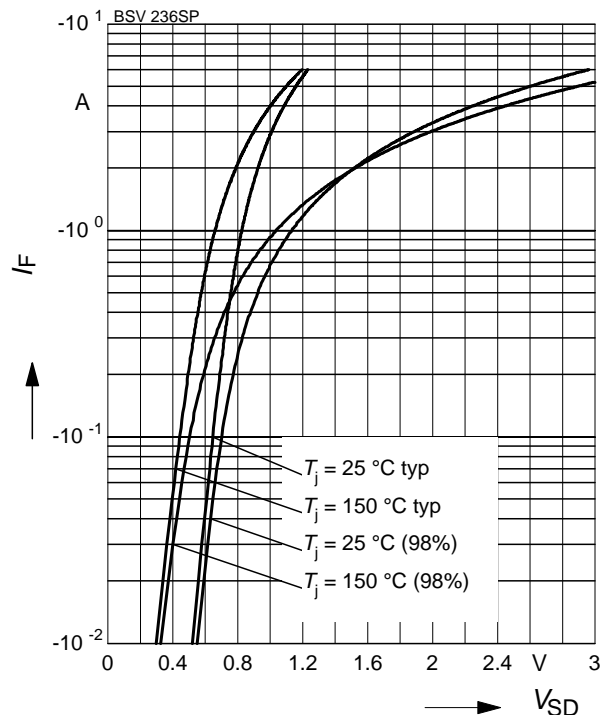
parameter: $V_{GS}=0$, $f=1 \text{ MHz}$



12 Forward character. of reverse diode

$$I_F = f(V_{SD})$$

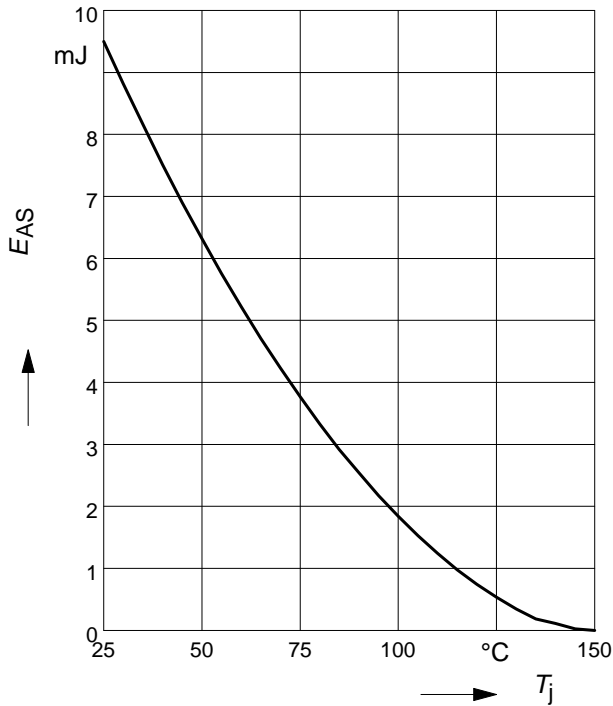
parameter: T_j , $t_p = 80 \mu\text{s}$



13 Typ. avalanche energy

$E_{AS} = f(T_j)$, par.: $I_D = -1.5\text{ A}$

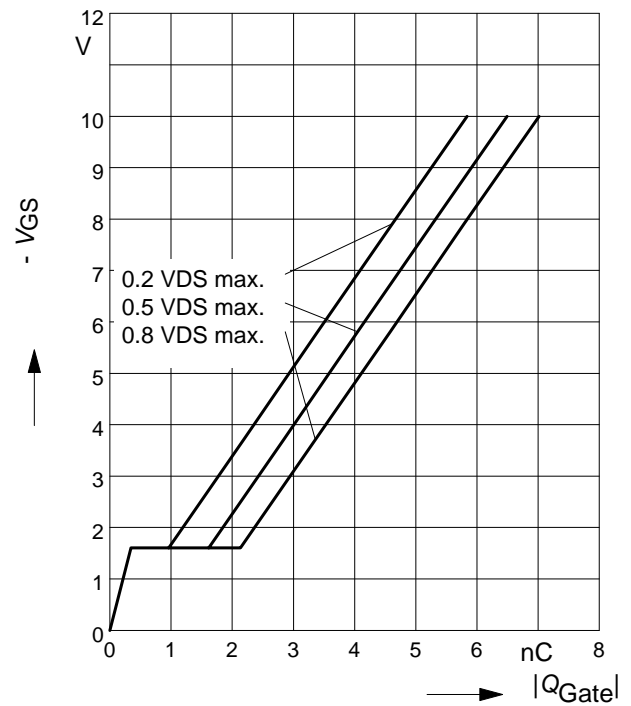
$V_{DD} = -10\text{ V}$, $R_{GS} = 25\ \Omega$



14 Typ. gate charge

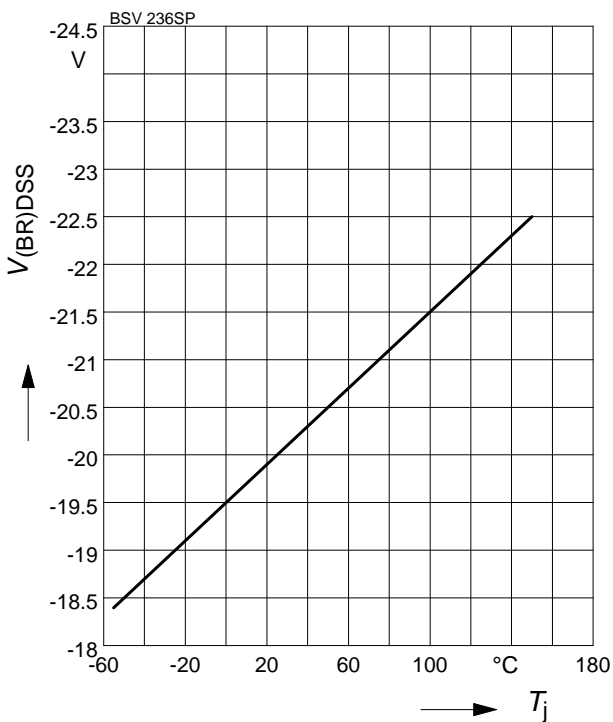
$|V_{GS}| = f(Q_{Gate})$

parameter: $I_D = -1.5\text{ A}$ pulsed



15 Drain-source breakdown voltage

$V_{(BR)DSS} = f(T_j)$





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